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NEW ATTY. DKT. 28951.5300
(previously YMOR:300)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 10/726,891

Confirmation No.: 4184

In re Application of:

Satoru KAMANO et al.

Group Art Unit: 2829

Filed: December 4, 2003

Examiner: Tung X. Nguyen

For: ANCILLARY EQUIPMENT FOR TESTING
SEMICONDUCTOR INTEGRATED CIRCUIT

AMENDMENT UNDER 37 CFR 1.116

Mail Stop AF
Commissioner for Patents
Customer Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In response to the Office Action mailed April 6, 2005 please amend the above-identified application as follows: